



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
**057810-0088**SERIAL NO.  
**10/790,759**APPLICANT  
**Eiji MARUYAMA**FILING DATE  
**March 03, 2004**GROUP  
**1709**

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
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		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number & Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
JS		EP 1 187 223 A2	03-13-2002	SANYO ELECTRIC CO., LTD		X	
JS		EP 0 892 590 A2	01-20-1999	TDK CORPORATION		X	
JS		EP 0 461 908 A2	12-18-1991	FUJITSU LIMITED		X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		<del>NEERINCK, D.G., et al., "Depth profiling of thin ITO films by grazing incidence X-ray diffraction", THIN SOLID FILMS, May 15, 1996, Pages 12-17, Elsevier Science S.A.</del>
JS		JOSHI, R.N., et al., "Characteristics of Indium tin oxide films deposited by r.f. magnetron sputtering", THIN SOLID FILMS, February 15, 1995, Pages 32-35, Elsevier Science S.A.
JS		THILAKAN, P., et al., "Oxidation dependent crystallization behaviour of IO and ITO thin films deposited by reactive thermal deposition technique", MATERIAL SCIENCE & ENGINEERING B, 1998, Pages 195-200, Elsevier Science S.A.
JS		European Search Report issued in corresponding European Patent Application No. EP 04 25 1457, dated April 13, 2007

EXAMINER  
/Jackson Smith/DATE CONSIDERED  
06/25/2007

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.